Abstracts

Accurate on Wafer Measurement of Phase and Amplitude of the Spectral Components of Incident and Scattered Voltage Waves at the Signal Ports of a Nonlinear Microwave Device

J. Verspecht, P. Debie, A. Barel and L. Martens. "Accurate on Wafer Measurement of Phase and Amplitude of the Spectral Components of Incident and Scattered Voltage Waves at the Signal Ports of a Nonlinear Microwave Device." 1995 MTT-S International Microwave Symposium Digest 95.3 (1995 Vol. III [MWSYM]): 1029-1032.

A measurement setup and calibration procedure are described allowing the accurate on wafer measurement of phases and amplitudes of the spectral components of incident and scattered voltage waves at the signal ports of a nonlinear microwave device. A comparison is made between measurements performed with the setup and simulations based on a Root-model.

❑ Return to main document.